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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/665,011	GYOUTOKU ET AL.	
Examiner	Art Unit	
Hai C. Pham	2861	

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Class	Subclass	Date	Examiner
347	122, 130, 224, 238, 244, 258	4/21/2006	HP
313	504	4/21/2006	HP
428	411.1	4/21/2006	HP
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Class	Subclass	Date	Examiner						
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